

MMBZxVAL series

Double ESD protection diodes for transient overvoltage suppression

Rev. 01 — 1 September 2008

Product data sheet

Product profile

1.1 General description

Unidirectional double ElectroStatic Discharge (ESD) protection diodes in a common anode configuration, encapsulated in a SOT23 (TO-236AB) small Surface-Mounted Device (SMD) plastic package. The devices are designed for ESD and transient overvoltage protection of up to two signal lines.

Table 1. **Product overview**

Type number[1]	Package	Package	
	NXP	JEDEC	
MMBZ12VAL	SOT23	TO-236AB	dual common anode
MMBZ15VAL			
MMBZ18VAL			
MMBZ20VAL			
MMBZ27VAL			
MMBZ33VAL			

^[1] All types available as /DG halogen-free version.

1.2 Features

- Unidirectional ESD protection of two lines
- Bidirectional ESD protection of one line IEC 61000-4-2; level 4 (ESD)
- Low diode capacitance: C_d ≤ 140 pF
- Rated peak pulse power: P_{PPM} ≤ 40 W
- Ultra low leakage current: I_{RM} ≤ 5 nA
- ESD protection up to 30 kV (contact discharge)
- IEC 61643-321
- AEC-Q101 qualified

1.3 Applications

- Computers and peripherals
- Audio and video equipment
- Cellular handsets and accessories
- Automotive electronic control units
- Portable electronics



1.4 Quick reference data

Table 2. Quick reference data

 $T_{amb} = 25 \,^{\circ}C$ unless otherwise specified.

1 amb - 23	C unless otherwise specifi					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per diode						
V_{RWM}	reverse standoff voltage					
	MMBZ12VAL MMBZ12VAL/DG		-	-	8.5	V
	MMBZ15VAL MMBZ15VAL/DG		-	-	12	V
	MMBZ18VAL MMBZ18VAL/DG		-	-	14.5	V
	MMBZ20VAL MMBZ20VAL/DG		-	-	17	V
	MMBZ27VAL MMBZ27VAL/DG		-	-	22	V
	MMBZ33VAL MMBZ33VAL/DG		-	-	26	V
C_d	diode capacitance	$f = 1 MHz; V_R = 0 V$				
	MMBZ12VAL MMBZ12VAL/DG		-	110	140	pF
	MMBZ15VAL MMBZ15VAL/DG		-	85	105	pF
	MMBZ18VAL MMBZ18VAL/DG		-	70	90	pF
	MMBZ20VAL MMBZ20VAL/DG		-	65	80	pF
	MMBZ27VAL MMBZ27VAL/DG		-	48	60	pF
	MMBZ33VAL MMBZ33VAL/DG		-	45	55	pF

2. Pinning information

Table 3. Pinning

Table 5.	i iiiiiiig		
Pin	Description	Simplified outline	Graphic symbol
1	cathode (diode 1)	—-	
2	cathode (diode 2)	3	3
3	common anode	1 2	1 2 006aaa154

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

Product data sheet

Ordering information 3.

Table 4 Ordering information

Table 4. Ordering information						
Type number	Package	Package				
	Name	Name Description				
MMBZ12VAL	-	plastic surface-mounted package; 3 leads	SOT23			
MMBZ15VAL						
MMBZ18VAL						
MMBZ20VAL						
MMBZ27VAL						
MMBZ33VAL						
MMBZ12VAL/DG	-	plastic surface-mounted package; 3 leads	SOT23			
MMBZ15VAL/DG						
MMBZ18VAL/DG						
MMBZ20VAL/DG						
MMBZ27VAL/DG						
MMBZ33VAL/DG						

Marking 4.

Table 5. **Marking codes**

Type number	Marking code ^[1]	Type number	Marking code[1]
MMBZ12VAL	*H1	MMBZ12VAL/DG	TH*
MMBZ15VAL	*H2	MMBZ15VAL/DG	TK*
MMBZ18VAL	*H3	MMBZ18VAL/DG	TM*
MMBZ20VAL	*H4	MMBZ20VAL/DG	TP*
MMBZ27VAL	*H5	MMBZ27VAL/DG	TR*
MMBZ33VAL	*H6	MMBZ33VAL/DG	TT*

^{[1] * = -:} made in Hong Kong

Product data sheet

^{* =} p: made in Hong Kong

^{* =} t: made in Malaysia

^{* =} W: made in China

Limiting values 5.

Table 6. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
Per diode					
P _{PPM}	rated peak pulse power	$t_p = 10/1000 \ \mu s$	[1][2] _	40	W
I _{PPM}	rated peak pulse current	$t_p = 10/1000 \ \mu s$	[1][2]		
	MMBZ12VAL MMBZ12VAL/DG		-	2.35	Α
	MMBZ15VAL MMBZ15VAL/DG		-	1.9	Α
	MMBZ18VAL MMBZ18VAL/DG		-	1.6	Α
	MMBZ20VAL MMBZ20VAL/DG		-	1.4	Α
	MMBZ27VAL MMBZ27VAL/DG		-	1	Α
	MMBZ33VAL MMBZ33VAL/DG		-	0.87	Α
Per device					
P _{tot}	total power dissipation	$T_{amb} \le 25 ^{\circ}C$	<u>[3]</u> _	265	mW
			<u>[4]</u> _	360	mW
Tj	junction temperature		-	150	°C
T _{amb}	ambient temperature		-55	+150	°C
T _{stg}	storage temperature		-65	+150	°C

^[1] In accordance with IEC 61643-321 (10/1000 µs current waveform).

ESD maximum ratings

 T_{amb} = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions		Min	Max	Unit
Per diode						
V _{ESD}	electrostatic discharge voltage	oltage				
		IEC 61000-4-2 (contact discharge)		-	30	kV
		machine model		-	2	kV

^[1] Device stressed with ten non-repetitive ESD pulses.

MMBZXVAL SER 1 © NXP B.V. 2008. All rights reserved. Rev. 01 — 1 September 2008

Downloaded from Arrow.com.

^[2] Measured from pin 1 or 2 to pin 3.

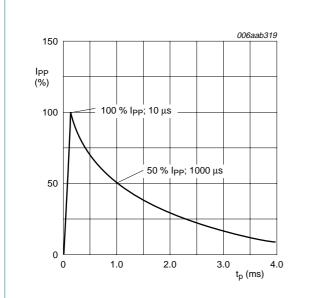
Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard

^[4] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for cathode 1 cm².

^[2] Measured from pin 1 or 2 to pin 3.

Table 8. ESD standards compliance

Standard	Conditions
Per diode	
IEC 61000-4-2; level 4 (ESD)	> 15 kV (air); > 8 kV (contact)
MIL-STD-883; class 3 (human body model)	> 8 kV



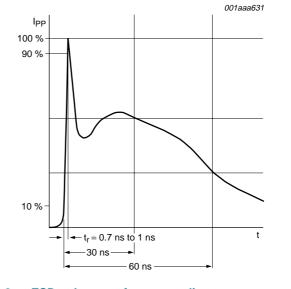


Fig 1. 10/1000 μ s pulse waveform according to IEC 61643-321

Fig 2. ESD pulse waveform according to IEC 61000-4-2

6. Thermal characteristics

Table 9. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per device	9					
$R_{th(j\text{-}a)} \qquad \text{thermal resistance from junction} \\ \text{to ambient}$,	n in free air	[1] -	-	460	K/W
	[2	[2] _	-	340	K/W	
$R_{th(j-sp)}$	thermal resistance from junction to solder point		[3] _	-	50	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for cathode 1 cm².
- [3] Measured from pin 1 or 2 to pin 3.

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

Product data sheet

7. Characteristics

Table 10. Characteristics

 $T_{amb} = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per diod	е					
V _F	forward voltage	I _F = 10 mA	-	-	0.9	V
V_{RWM}	reverse standoff voltage					
	MMBZ12VAL MMBZ12VAL/DG		-	-	8.5	V
	MMBZ15VAL MMBZ15VAL/DG		-	-	12	V
	MMBZ18VAL MMBZ18VAL/DG		-	-	14.5	V
	MMBZ20VAL MMBZ20VAL/DG		-	-	17	V
	MMBZ27VAL MMBZ27VAL/DG		-	-	22	V
	MMBZ33VAL MMBZ33VAL/DG		-	-	26	V
I _{RM}	reverse leakage current					
	MMBZ12VAL MMBZ12VAL/DG	$V_{RWM} = 8.5 V$	-	0.1	5	nA
	MMBZ15VAL MMBZ15VAL/DG	V _{RWM} = 12 V	-	0.1	5	nA
	MMBZ18VAL MMBZ18VAL/DG	V _{RWM} = 14.5 V	-	0.1	5	nA
	MMBZ20VAL MMBZ20VAL/DG	$V_{RWM} = 17 V$	-	0.1	5	nA
	MMBZ27VAL MMBZ27VAL/DG	V _{RWM} = 22 V	-	0.1	5	nA
	MMBZ33VAL MMBZ33VAL/DG	V _{RWM} = 26 V	-	0.1	5	nA
V_{BR}	breakdown voltage	I _R = 1 mA				
	MMBZ12VAL MMBZ12VAL/DG		11.4	12	12.6	V
	MMBZ15VAL MMBZ15VAL/DG		14.25	15	15.75	V
	MMBZ18VAL MMBZ18VAL/DG		17.1	18	18.9	V
	MMBZ20VAL MMBZ20VAL/DG		19	20	21	V
	MMBZ27VAL MMBZ27VAL/DG		25.65	27	28.35	V
	MMBZ33VAL MMBZ33VAL/DG		31.35	33	34.65	V

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

MMBZxVAL series

Double ESD protection diodes for transient overvoltage suppression

Table 10. Characteristics ...continued

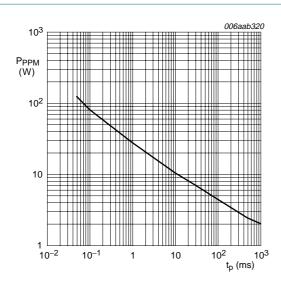
 T_{amb} = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions	N	/lin	Тур	Max	Unit
C _d	diode capacitance	$f = 1 MHz; V_R = 0 V$					
	MMBZ12VAL MMBZ12VAL/DG		-		110	140	pF
	MMBZ15VAL MMBZ15VAL/DG		-		85	105	pF
	MMBZ18VAL MMBZ18VAL/DG		-		70	90	pF
	MMBZ20VAL MMBZ20VAL/DG		-		65	80	pF
	MMBZ27VAL MMBZ27VAL/DG		-		48	60	pF
	MMBZ33VAL MMBZ33VAL/DG		-		45	55	pF
V_{CL}							
	MMBZ12VAL MMBZ12VAL/DG	$I_{PPM} = 2.35 A$	-		-	17	V
	MMBZ15VAL MMBZ15VAL/DG	$I_{PPM} = 1.9 A$	-		-	21	V
	MMBZ18VAL MMBZ18VAL/DG	I _{PPM} = 1.6 A	-		-	25	V
	MMBZ20VAL MMBZ20VAL/DG	$I_{PPM} = 1.4 A$	-		-	28	V
	MMBZ27VAL MMBZ27VAL/DG	$I_{PPM} = 1 A$	-		-	40	V
	MMBZ33VAL MMBZ33VAL/DG	$I_{PPM} = 0.87 \text{ A}$	-		-	46	V
Sz	temperature coefficient	$I_Z = 1 \text{ mA}$					
	MMBZ12VAL MMBZ12VAL/DG		-		8.2	-	mV/K
	MMBZ15VAL MMBZ15VAL/DG		-		11	-	mV/K
	MMBZ18VAL MMBZ18VAL/DG		-		14	-	mV/K
	MMBZ20VAL MMBZ20VAL/DG		-		15.8	-	mV/K
	MMBZ27VAL MMBZ27VAL/DG		-		23	-	mV/K
	MMBZ33VAL MMBZ33VAL/DG		-		29.8	-	mV/K

^[1] In accordance with IEC 61643-321(10/1000 µs current waveform).

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

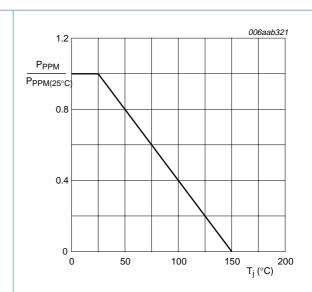
^[2] Measured from pin 1 or 2 to pin 3.



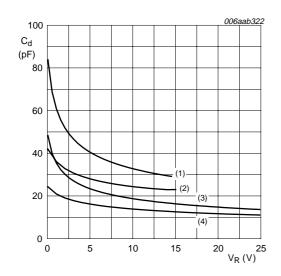
MMBZ27VAL: unidirectional and bidirectional

T_{amb} = 25 °C

Fig 3. Rated peak pulse power as a function of exponential pulse duration (rectangular waveform); typical values



Relative variation of rated peak pulse power as Fig 4. a function of junction temperature; typical values



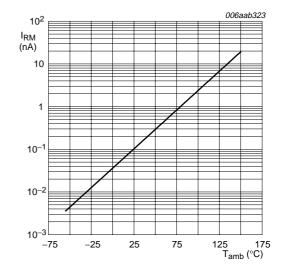
f = 1 MHz; $T_{amb} = 25 ^{\circ}\text{C}$

(1) MMBZ15VAL: unidirectional

(2) MMBZ15VAL: bidirectional

(3) MMBZ27VAL: unidirectional (4) MMBZ27VAL: bidirectional

Fig 5. Diode capacitance as a function of reverse voltage; typical values



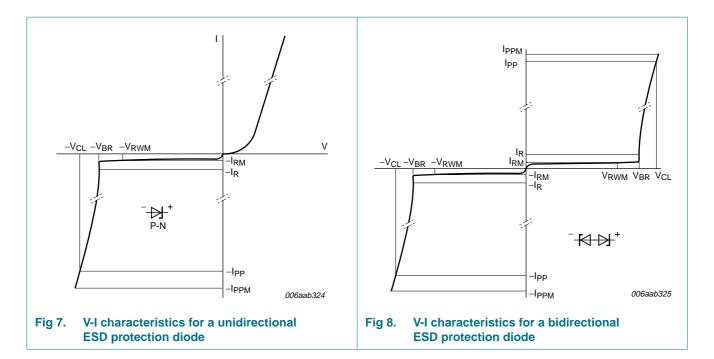
MMBZ27VAL: $V_{RWM} = 22 \text{ V}$

Fig 6. Reverse leakage current as a function of ambient temperature; typical values

8 of 15

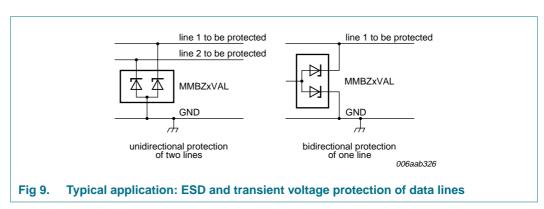
MMBZXVAL SER 1 © NXP B.V. 2008. All rights reserved. Rev. 01 — 1 September 2008

Product data sheet



Application information 8.

The MMBZxVAL series is designed for the protection of up to two unidirectional data or signal lines from the damage caused by ESD and surge pulses. The devices may be used on lines where the signal polarities are either positive or negative with respect to ground. The devices provide a surge capability of 40 W per line for a 10/1000 µs waveform.



MMBZXVAL SER 1

Product data sheet

Circuit board layout and protection device placement

Circuit board layout is critical for the suppression of ESD, Electrical Fast Transient (EFT) and surge transients. The following guidelines are recommended:

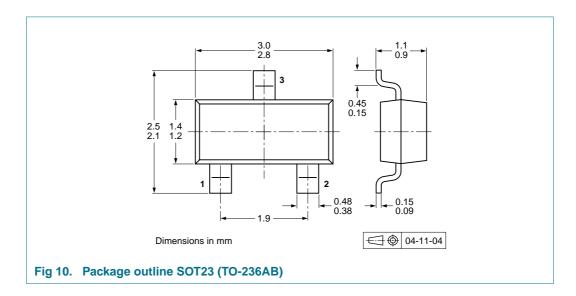
- 1. Place the devices as close to the input terminal or connector as possible.
- 2. The path length between the device and the protected line should be minimized.
- 3. Keep parallel signal paths to a minimum.
- 4. Avoid running protected conductors in parallel with unprotected conductors.
- 5. Minimize all Printed-Circuit Board (PCB) conductive loops including power and ground loops.
- 6. Minimize the length of the transient return path to ground.
- 7. Avoid using shared transient return paths to a common ground point.
- 8. Ground planes should be used whenever possible. For multilayer PCBs, use ground vias.

Test information 9_

9.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q101 - Stress test qualification for discrete semiconductors, and is suitable for use in automotive applications.

10. Package outline



MMBZXVAL SER 1

Product data sheet

11. Packing information

Table 11. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

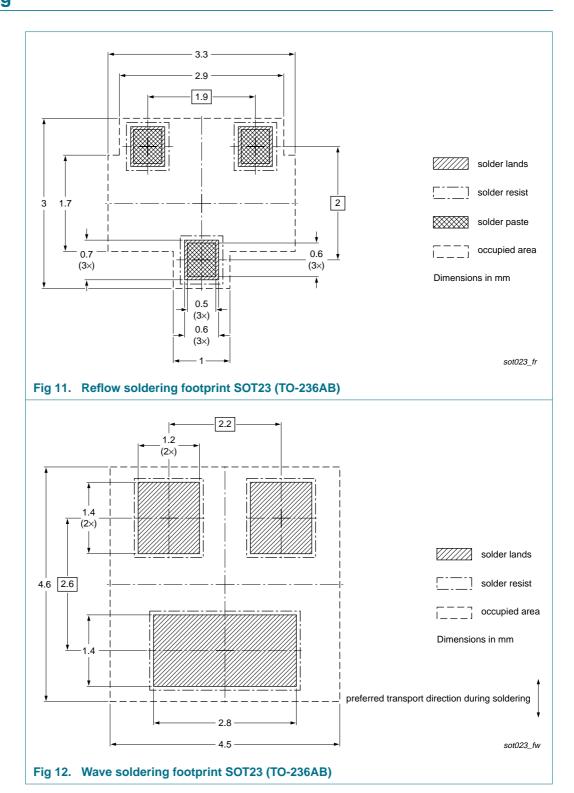
Type number	Package	Description	Packing	Packing quantity		
			3000	10000		
MMBZ12VAL	SOT23	4 mm pitch, 8 mm tape and reel	-215	-235		
MMBZ15VAL						
MMBZ18VAL						
MMBZ20VAL						
MMBZ27VAL						
MMBZ33VAL						
MMBZ12VAL/DG	SOT23	4 mm pitch, 8 mm tape and reel	-215	-235		
MMBZ15VAL/DG						
MMBZ18VAL/DG						
MMBZ20VAL/DG						
MMBZ27VAL/DG						
MMBZ33VAL/DG						

^[1] For further information and the availability of packing methods, see Section 15.

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

Product data sheet

12. Soldering



MMBZXVAL SER 1 Rev. 01 — 1 September 2008

Product data sheet



13. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
MMBZXVAL_SER_1	20080901	Product data sheet	-	-

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

Product data sheet Rev. 01 — 1 September 2008 13 of 15



14. Legal information

14.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

14.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

14.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

ESD protection devices — These products are only intended for protection against ElectroStatic Discharge (ESD) pulses and are not intended for any other usage including, without limitation, voltage regulation applications. NXP Semiconductors accepts no liability for use in such applications and therefore such use is at the customer's own risk.

14.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

15. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

MMBZXVAL_SER_1 © NXP B.V. 2008. All rights reserved.

MMBZxVAL series

Double ESD protection diodes for transient overvoltage suppression

16. Contents

1	Product profile
1.1	General description
1.2	Features
1.3	Applications
1.4	Quick reference data
2	Pinning information 2
3	Ordering information
4	Marking 3
5	Limiting values 4
6	Thermal characteristics 5
7	Characteristics 6
8	Application information 9
9	Test information
9.1	Quality information
10	Package outline 10
11	Packing information 11
12	Soldering 12
13	Revision history
14	Legal information 14
14.1	Data sheet status
14.2	Definitions
14.3	Disclaimers
14.4	Trademarks14
15	Contact information 14
16	Contents

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.





© NXP B.V. 2008.

All rights reserved.

For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 1 September 2008

Document identifier: MMBZXVAL_SER_1